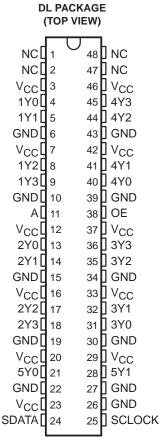
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- High-Speed, Low-Skew 1-to-18 Clock Buffer for Synchronous DRAM (SDRAM) Clock Buffering Applications
- Output Skew, t<sub>sk(o)</sub>, Less Than 250 ps
- Pulse Skew, t<sub>sk(p)</sub>, Less Than 500 ps
- Supports up to Four Unbuffered SDRAM Dual Inline Memory Modules (DIMMs)
- I<sup>2</sup>C Serial Interface Provides Individual Enable Control for Each Output
- Operates at 3.3 V
- Distributed V<sub>CC</sub> and Ground Pins Reduce Switching Noise
- 100-MHz Operation
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015
- Packaged in 48-Pin Shrink Small Outline (DL) Package

### description

The CDC318A is a high-performance clock buffer designed to distribute high-speed clocks in PC applications. This device distributes one input (A) to 18 outputs (Y) with minimum skew for clock distribution. The CDC318A operates from a 3.3-V power supply. It is characterized for operation from 0°C to 70°C.

This device has been designed with consideration for optimized EMI performance. Depending on the application layout, damping resistors in series to the clock outputs (like proposed in the PC100 specification) may not be needed in most cases.



NC - No internal connection

The device provides a standard mode (100K-bits/s)  $I^2C$  serial interface for device control. The implementation is as a slave/receiver. The device address is specified in the  $I^2C$  device address table. Both of the  $I^2C$  inputs (SDATA and SCLOCK) are 5-V tolerant and provide integrated pullup resistors (typically 140 k $\Omega$ ).

Three 8-bit I<sup>2</sup>C registers provide individual enable control for each of the outputs. All outputs default to enabled at powerup. Each output can be placed in a disabled mode with a low-level output when a low-level control bit is written to the control register. The registers are write only and must be accessed in sequential order (i.e., random access of the registers is not supported).

The CDC318A provides 3-state outputs for testing and debugging purposes. The outputs can be placed in a high-impedance state via the output-enable (OE) input. When OE is high, all outputs are in the operational state. When OE is low, the outputs are placed in a high-impedance state. OE provides an integrated pullup resistor.



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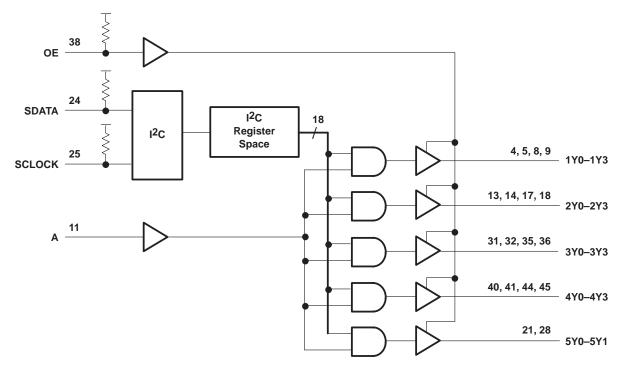
## **CDC318A** 1-LINE TO 18-LINE CLOCK DRIVER WITH I<sup>2</sup>C CONTROL INTERFACE SCAS614 - SEPTEMBER 1998

### **FUNCTION TABLE**

INP	JTS			OUTPUTS		
OE	Α	1Y0-1Y3	2Y0-2Y3	3Y0-3Y3	4Y0-4Y3	5Y0-5Y1
L	Х	Hi-Z	Hi-Z	Hi-Z	Hi-Z	Hi-Z
Н	L	L	L	L	L	L
Н	Н	Н <sup>†</sup>	н†	н†	н†	H <sup>†</sup>

<sup>†</sup> The function table assumes that all outputs are enabled via the appropriate I<sup>2</sup>C configuration register bit. If the output is disabled via the appropriate configuration bit, then the output is driven to a low state, regardless of the state of the A input.

## logic diagram (positive logic)



## **Terminal Functions**

	TERMINAL NAME NO.		TERMINAL I/O		DECORIDATION
NAME			DESCRIPTION		
1Y0-1Y3	4, 5, 8, 9	0	3.3-V SDRAM byte 0 clock outputs		
2Y0-2Y3	13, 14, 17, 18	0	3.3-V SDRAM byte 1 clock outputs		
3Y0-3Y3	31, 32, 35, 36	0	3.3-V SDRAM byte 2 clock outputs		
4Y0-4Y3	40, 41, 44, 45	0	3.3-V SDRAM byte 3 clock outputs		
5Y0-5Y1	21, 28	0	3.3-V clock outputs provided for feedback control of external phase-locked loops (PLLs)		
А	11	I	Clock input		
OE	38	I	Output enable. When asserted, OE puts all outputs in a high-impedance state. A nominal $140$ -k $\Omega$ pullup resistor is internally integrated.		
SCLOCK	25	I	I <sup>2</sup> C serial clock input. A nominal 140-k $\Omega$ pullup resistor is internally integrated.		
SDATA	24	I/O	Bidirectional I $^2$ C serial data input/output. A nominal 140-k $\Omega$ pullup resistor is internally integrated.		
GND	6, 10, 15, 19, 22, 26, 27, 30, 34, 39, 43		Ground		
NC	1, 2, 47, 48		No internal connection. Reserved for future use.		
VCC	3, 7, 12, 16, 20, 23, 29, 33, 37, 42, 46		3.3-V power supply		

## I<sup>2</sup>C DEVICE ADDRESS

A7	A6	A5	A4	А3	A2	A1	A0 (R/W)
Н	Н	L	Н	L	L	Н	_

### I<sup>2</sup>C BYTE 0-BIT DEFINITION<sup>†</sup>

BIT	DEFINITION	DEFAULT VALUE
7	2Y3 enable (pin 18)	Н
6	2Y2 enable (pin 17)	Н
5	2Y1 enable (pin 14)	Н
4	2Y0 enable (pin 13)	Н
3	1Y3 enable (pin 9)	Н
2	1Y2 enable (pin 8)	Н
1	1Y1 enable (pin 5)	Н
0	1Y0 enable (pin 4)	Н

<sup>†</sup>When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.



## CDC318A 1-LINE TO 18-LINE CLOCK DRIVER WITH I<sup>2</sup>C CONTROL INTERFACE

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### I<sup>2</sup>C BYTE 1-BIT DEFINITION<sup>†</sup>

BIT	DEFINITION	DEFAULT VALUE
7	4Y3 enable (pin 45)	Н
6	4Y2 enable (pin 44)	Н
5	4Y1 enable (pin 41)	Н
4	4Y0 enable (pin 40)	Н
3	3Y3 enable (pin 36)	Н
2	3Y2 enable (pin 35)	Н
1	3Y1 enable (pin 32)	Н
0	3Y0 enable (pin 31)	Н

<sup>†</sup> When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.

### I<sup>2</sup>C BYTE 2-BIT DEFINITION<sup>†</sup>

BIT	DEFINITION	DEFAULT VALUE
7	5Y1 enable (pin 28)	Н
6	5Y0 enable (pin 21)	Н
5	Reserved	Н
4	Reserved	Н
3	Reserved	Н
2	Reserved	Н
1	Reserved	Н
0	Reserved	Н

<sup>†</sup>When the value of the bit is high, the output is enabled. When the value of the bit is low, the output is forced to a low state. The default value of all bits is high.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 4.6 V
Input voltage range, V <sub>I</sub> (see Note 1)	
Input voltage range, V <sub>I</sub> (SCLOCK, SDATA) (see Note 1)	0.5 V to 6.5 V
Output voltage range, V <sub>O</sub> (SDATA) (see Note 1)	0.5 V to 6.5 V
Voltage range applied to any output in the high or power-off state, V <sub>O</sub>	$\dots$ -0.5 V to V <sub>CC</sub> +0.5 V
Current into any output in the low state (except SDATA), IO	48 mA
Current into SDATA in the low state, I <sub>O</sub>	12 mA
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0) (SCLOCK)	–50 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0) (SDATA)	–50 mA
Package thermal impedance, $\theta_{JA}$ (see Notes 2 and 3)	84°C/W
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

- The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero. The absolute maximum power dissipation allowed at T<sub>A</sub> = 55°C (in still air) is 1.2 W.
- 3. Thermal impedance ( $\Theta_{JA}$ ) can be considerably lower if the device is soldered on the PCB board with a copper layer underneath the package. A simulation on a PCB board (3 in. × 3 in.) with two internal copper planes (1 oz. cu, 0.036 mm thick) and 0.071 mm cu (202) in area underneath the package, resulted in  $\Theta_{JA} = 60^{\circ}$ C/W. This would allow 1.2 W total power dissipation at TA =  $70^{\circ}$ C.

## recommended operating conditions (see Note 4)

			MIN	TYP	MAX	UNIT
Vcc	3.3-V core supply voltage		3.135		3.465	V
		A, OE	2		V <sub>CC</sub> +0.3	V
V <sub>IH</sub>	High-level input voltage	SDATA, SCLOCK (see Note 3)	2.2		5.5	V
		A, OE	-0.3		0.8	V
V <sub>IL</sub>	Low-level input voltage	SDATA, SCLOCK (see Note 3)	0		1.04	V
loh	High-level output current	Y outputs			-36	mA
loL	Low-level output current	Y outputs			24	mA
rį	Input resistance to V <sub>CC</sub>	SDATA, SCLOCK (see Note 3)		140		kΩ
f(SCL)	SCLOCK frequency				100	kHz
t(BUS)	Bus free time		4.7			μs
t <sub>su(START)</sub>	START setup time		4.7			μs
th(START)	START hold time		4			μs
tw(SCLL)	SCLOCK low pulse duration		4.7			μs
tw(SCLH)	SCLOCK high pulse duration		4			μs
<sup>t</sup> r(SDATA)	SDATA input rise time				1000	ns
tf(SDATA)	SDATA input fall time				300	ns
t <sub>su(SDATA)</sub>	SDATA setup time		250			ns
th(SDATA)	SDATA hold time		20			ns
t <sub>su(STOP)</sub>	STOP setup time		4			μs
TA	Operating free-air temperature		0		70	°C

NOTE 4: The CMOS-level inputs fall within these limits:  $V_{IH}$  min =  $0.7 \times V_{CC}$  and  $V_{IL}$  max =  $0.3 \times V_{CC}$ .



## CDC318A 1-LINE TO 18-LINE CLOCK DRIVER WITH I<sup>2</sup>C CONTROL INTERFACE SCAS614 – SEPTEMBER 1998

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CON	IDITIONS	MIN	TYP	MAX	UNIT	
VIK	Input clamp voltage		V <sub>CC</sub> = 3.135 V,	I <sub>I</sub> = -18 mA			-1.2	V	
Vон	High-level output voltage	Y outputs	V <sub>CC</sub> = Min to Max,	I <sub>OH</sub> = -1 mA	V <sub>CC</sub> – 0.1 V			V	
			V <sub>CC</sub> = 3.135 V,	I <sub>OH</sub> = -36 mA	2.4				
		Y outputs	V <sub>CC</sub> = Min to Max,	$I_{OL} = 1 \text{ mA}$			0.1		
\/a.	Low-level output voltage	1 outputs	V <sub>CC</sub> = 3.135 V,	I <sub>OL</sub> = 24 mA			0.4	V	
VOL	Low-level output voltage	SDATA	V 0.40EV	$I_{OL} = 3 \text{ mA}$			0.4	V	
		SDATA	V <sub>CC</sub> = 3.135 V	I <sub>OL</sub> = 6 mA			0.6		
		SDATA	V <sub>CC</sub> = 3.135 V,	VO = VCC MAX			20	μΑ	
	Lligh lavel autout augrant		V <sub>CC</sub> = 3.135 V,	V <sub>O</sub> = 2 V	-54		-126		
ЮН	High-level output current	Y outputs	V <sub>CC</sub> = 3.3 V,	V <sub>O</sub> = 1.65 V		-92		mA	
			V <sub>CC</sub> = 3.465 V,	V <sub>O</sub> = 3.135 V	-21		-46		
			V <sub>CC</sub> = 3.135 V,	V <sub>O</sub> = 1 V	49		118		
lOL	Low-level output current	Y outputs	V <sub>CC</sub> = 3.3 V,	V <sub>O</sub> = 1.65 V		93		mA	
			V <sub>CC</sub> = 3.465 V,	V <sub>O</sub> = 0.4 V	24		53		
		А					5		
lіН	High-level input current	OE	V <sub>CC</sub> = 3.465 V,	VI = VCC			20	μΑ	
		SCLOCK, SDATA	1				20	7	
		А					-5		
Ι <sub>Ι</sub> L	Low-level input current	OE	V <sub>CC</sub> = 3.465 V,	$V_I = GND$	-10		-50	μΑ	
		SCLOCK, SDATA	1		-10		-50		
loz	High-impedance-state outp	ut current	V <sub>CC</sub> = 3.465 V,	V <sub>O</sub> = 3.465 V or 0			±10	μΑ	
l <sub>off</sub>	Off-state current	SCLOCK, SDATA	V <sub>CC</sub> = 0,	V <sub>I</sub> = 0 V to 5.5 V			50	μΑ	
ICC	Supply current		V <sub>CC</sub> = 3.465 V,	IO = 0		0.2	0.5	mA	
ΔICC	Change in supply current		$V_{CC} = 3.135 \text{ V to } 3.46$ One input at $V_{CC} = 0$ . All other inputs at $V_{CC}$	6 V,			500	μА	
	Dynamic I <sub>CC</sub> at 100 MHz		V <sub>CC</sub> = 3.465 V,	C <sub>L</sub> = 20 pF,		230		mA	
Cl	Input capacitance		$V_I = V_{CC}$ or GND,	V <sub>C</sub> C = 3.3 V		4		pF	
CO	Output capacitance		$V_O = V_{CC}$ or GND,			6		pF	
C <sub>I/O</sub>	SDATA I/O capacitance		$V_{I/O} = V_{CC}$ or GND,	Vcc = 3.3 V		7		pF	

## **CDC318A** 1-LINE TO 18-LINE CLOCK DRIVER WITH I<sup>2</sup>C CONTROL INTERFACE SCAS614 - SEPTEMBER 1998

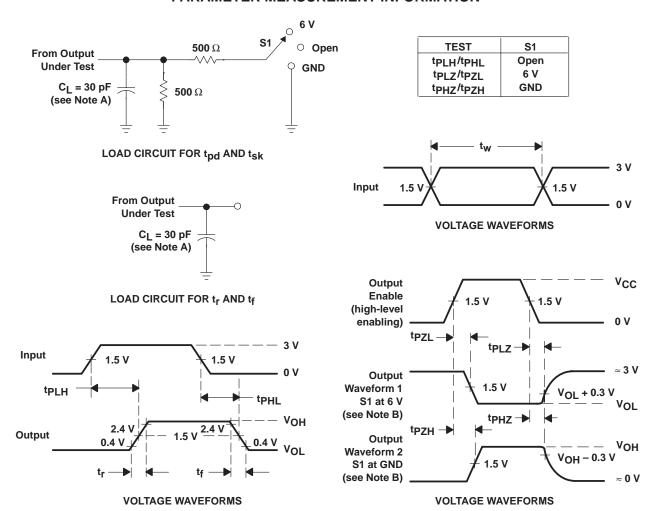
## switching characteristics over recommended operating conditions

	PARAMETER			то	TEST CONDITIONS	MIN	MAX	UNIT
			А	Υ		1.2	4.5	ns
<sup>t</sup> PLH	Low-to-high level propagation delay time		SCLOCK↓	SDATA valid	$V_{CC}$ = 3.3 V ±0.165 V, See Figure 3		2	μs
<sup>t</sup> PLH	Low-to-high level propagation of	delay time	SDATA↑	Υ	V <sub>CC</sub> = 3.3 V ±0.165 V, See Figure 3		150	ns
			А	Y		1.2	4.5	ns
tPHL	High-to-low level propagation of	lelay time	SCLOCK↓	SDATA valid	V <sub>CC</sub> = 3.3 V ±0.165 V, See Figure 3		2	μs
<sup>t</sup> PHL	High-to-low level propagation delay time		SDATA↑	Υ	$V_{CC} = 3.3 \text{ V} \pm 0.165 \text{ V},$ See Figure 3		150	ns
<sup>t</sup> PZH	Enable time to the high level		OE	Y		1	7	no
tPZL	Enable time to the low level			Ť		1	7	ns
<sup>t</sup> PHZ	Disable time from the high level		OE	Y		1	7	ns
<sup>t</sup> PLZ	Disable time from the low level			·		1	7	115
t <sub>sk(o)</sub>	Skew time		А	Υ			250	ps
t <sub>sk(p)</sub>	Skew time		А	Υ			500	ps
tsk(pr)	Skew time		А	Υ			1	ns
t <sub>r</sub>	Rise time			Υ		0.5	2.2	ns
	Rise time (see Note 5 and	SDATA			C <sub>L</sub> = 10 pF	6		ns
t <sub>r</sub>	Figure 3)	SDAIA			$C_L = 400 \text{ pF}$		950	115
t <sub>f</sub>	Fall time			Y		0.5	2.3	ns
4.	Fall time (see Note 5 and	SDATA			C <sub>L</sub> = 10 pF	20		
t <sub>f</sub>	Figure 3)	SDATA			C <sub>L</sub> = 400 pF		250	ns

NOTE 5: This parameter has a lower limit than BUS specification. This allows use of series resistors for current spike protection.

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### PARAMETER MEASUREMENT INFORMATION



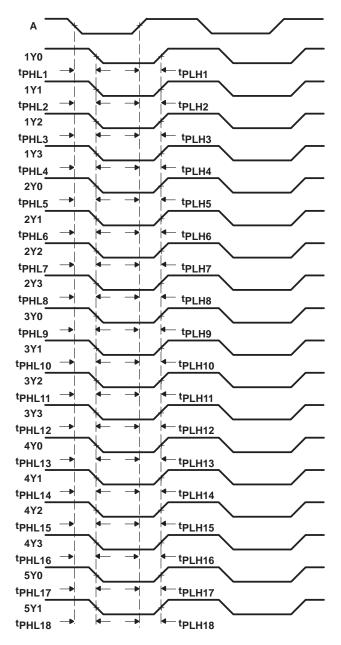
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50~\Omega$ ,  $t_f \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



### PARAMETER MEASUREMENT INFORMATION



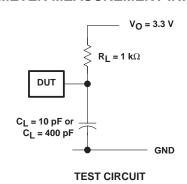
NOTES: A. Output skew,  $t_{Sk(0)}$ , is calculated as the greater of:

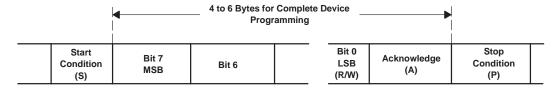
- The difference between the fastest and slowest of tp<sub>LHn</sub> (n = 1:18)
   The difference between the fastest and slowest of tp<sub>HLn</sub> (n = 1:18)
- B. Pulse skew,  $t_{sk(p)}$ , is calculated as the greater of  $|t_{PLHn} t_{PHLn}|$  (n = 1:18)
- C. Process skew,  $t_{sk(pr)}$ , is calculated as the greater of:
  - The difference between the fastest and slowest of tpLHn (n = 1:18) across multiple devices under identical operating conditions
  - The difference between the fastest and slowest of tpHLn (n = 1:18) across multiple devices under identical operating conditions

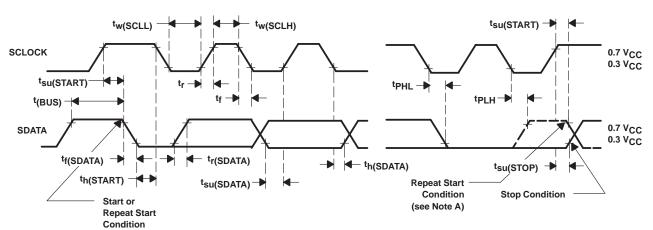
Figure 2. Waveforms for Calculation of  $t_{sk(p)}$ ,  $t_{sk(p)}$ ,  $t_{sk(pr)}$ 



## PARAMETER MEASUREMENT INFORMATION







### **VOLTAGE WAVEFORMS**

BYTE	DESCRIPTION			
1	I <sup>2</sup> C address			
2	Command (dummy value, ignored)			
3	Byte count (dummy value, ignored)			
4	I <sup>2</sup> C data byte 0			
5	I <sup>2</sup> C data byte 1			
6	I <sup>2</sup> C data byte 2			

NOTES: A. The repeat start condition is not supported.

B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  100 kHz,  $Z_O = 50 \Omega$ ,  $t_f \geq$  10 ns.  $t_f \geq$  10 ns.

Figure 3. Propagation Delay Times, tr and tf



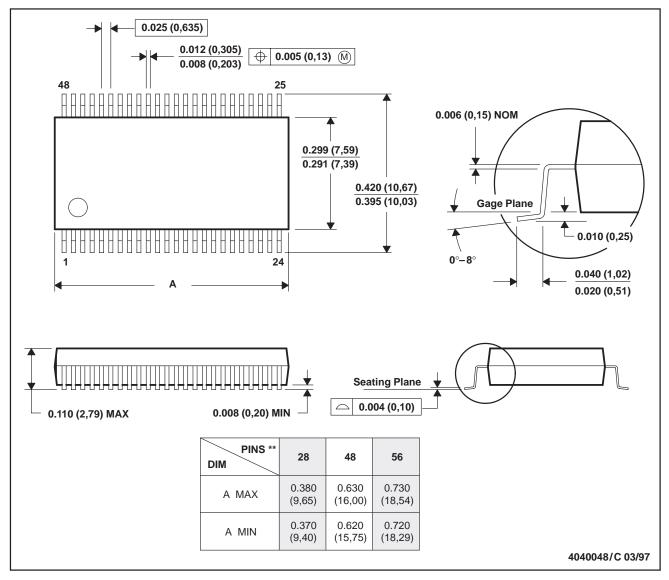
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## **MECHANICAL INFORMATION**

## DL (R-PDSO-G\*\*)

### PLASTIC SMALL-OUTLINE PACKAGE

### **48 PIN SHOWN**



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MO-118

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